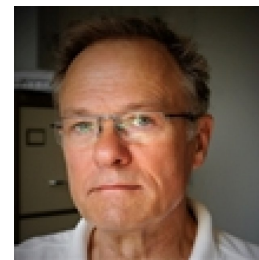


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Sven Tougaard earned the MS (1975) at the Technical University, Copenhagen, Denmark, and the PhD (1979) and dr. scient (1988) degrees in theoretical and experimental surface physics at Odense University, Denmark. He was post. doc. in USA and Germany (1978-84) and professor at the University of Southern Denmark since 1984. He founded the software company QUASES-Tougaard Inc. (1994) (www.quases.com) which develops software for characterization of the composition and electronic properties of surface nanostructures by X-ray photoelectron spectroscopy (XPS) and reflection electron energy loss spectroscopy (REELS). Prof. Tougaard received the Fyns Stitstidendes Research Prize in 1987, the Rivière Prize awarded by the UK Surface Analysis Forum in 2007, "for work which has been judged outstanding in its continuing and lasting contribution to surface analysis", and the Albert Nerken Award by the American Vacuum Society in 2012 "for contributions to the development of improved methods to characterize thin-film nanostructures by X-ray photoelectron spectroscopy". His current research focuses on experimental and theoretical studies of phenomena induced by the electron-solid interaction at surfaces and in nanostructures and development of theory for practical experimental methods to determine the chemical composition and electronic properties of nanostructures by electron spectroscopy. He has conducted and participated in several EU supported international projects on these subjects, published more than 200 scientific papers that are cited more than 7000 times with an H-index = 42 and presented more than 60 invited talks at international conferences and workshops. He has a long-standing active scientific collaboration with several research institutes in Europe, USA, Korea and Japan. He is on the Steering Committee for ECASIA (European Conf. for Surface and Interface Analysis) (2002-) and has served on the program committees and advisory boards for more than 25 international conferences and workshops. He serves on the editorial board for the journals: J. Electron Spectroscopy (1990-2012), Surface and Interface Anal. (1989-), J. of Surface Analysis (1994-), and Surface Science Spectra (1991-).

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Comparison of source functions obtained by using QUASES and the Partial Intensity Analyses for inelastic background correction: KLL Auger spectra of 3d transition elements Cu and Ni

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Comparison of the Tougaard, ARXPS, RBS and Ellipsometry methods to determine the thickness of thin SiO₂ layers

Semak, B. S., Marel, C. V. D. & Tougaard, S., 2002, I : Surface and Interface Analysis. 33, s. 238-44

Deposition and characterization of ITO films produced by laser ablation at 355 nm

Holmelund, E., Thestrup, B., Schou, J., Larsen, N. B., Nielsen, M. M., Johnson, E. & Tougaard, S., 2002, I : Applied Physics A: Materials Science & Processing. s. A74; 147-52

Determination of Inelastic Mean Free Path of High Energy Electrons from Shape Analysis of K- Auger and K- conversion Spectra Emitted from Thin Films

Köver, L., Tougaard, S., Toth, J., Varga, D., Dragoun, O., Koval'k, A. & Rysavy, M., 2002, I : Journal of Surface Analysis. 9, s. 281-4

Experimental estimation of surface excitation parameter for surface analysis

Gergely, G., Menyhard, M., Gurban, S., Sulyok, A., Toth, J., Varga, D. & Tougaard, S., 2002, I : Surface and Interface Analysis. s. 33; 410-3

Pure and Sn-doped ZnO films produced by pulsed laser deposition

Holmelund, E., Schou, J., Tougaard, S. & Larsen, N. B., 2002, I : Applied Surface Science. s. 197-198; 467-71

Recent progress in silicon oxidation: Towards ultra thin oxides

Morgen, P., K.-Dam, F., Gundlach, C., Jensen, T., Tækker, L.-B., Tougaard, S. & Pedersen, K., 2002, I : Recent Res Devel Appl Phys. 5, s. 287-311

Surface Morphology of SiO₂ grown on a Si(111)7x7 surface by alternating exposure to Caesium and Oxygen and Subsequent Annealing

Semak, B. S., Jensen, T., Tækker, L. B., Morgen, P. & Tougaard, S., 2002, I : Surf. Sci.. s. 498; 11-20.

Determination of overlayer thickness by QUASES analysis of photon excited KLL Auger spectra of Ni and Cu films

Kövé, L., Tougaard, S., Tóth, J., Daróczy, L., Szabó, I., Langer, G. & Menyhárd, M., 2001, I : Surface and Interface Analysis. 31, s. 271B9

Intercomparison of Methods for Separation of REELS Elastic Peak Intensities for Determination of IMFP

Tougaard, S., Krawczyk, M., Jablonski, A., Pavluch, J., Tóth, J., Varga, D., Gergely, G., Menyhárd, M. & Sulyok, A., 2001, I : Surface and Interface Analysis. 31, s. 1-10

Practical Correction Procedures for Elastic Electron Scattering Effects in ARXPS

Lassen, T. S., Tougaard, S. & Jablonski, A., 2001, I : Surf. Sci.. 481, s. 150-62

Probing the ex situ morphology of Ge islands on Si(001): AFM and XPS inelastic peak shape analysis

Simonsen, A. C., Tougaard, S., Lundsgaard Hansen, J. & Nylandsted Larsen, A., 2001, I : Surface and Interface Analysis. 31, 4, s. 328-337 10 s.

Quantification of Well-characterized Langmuir-Blodgett Film by Analysis of the PeakShape of XPS taken at Different Emission Angles.

Suzuki, N., Kato, T. & Tougaard, S., 2001, I : Surface and Interface Analysis. 31, s. 862-8

Surface Excitation Effects in Electron Spectroscopy

Gergely, G., Menyhárd, M., Gurban, S., Sulyok, A., Tóth, J., Varga, D. & Tougaard, S., 2001, I : Solid State Ionics. 141-142, s. 47-51

Surface Morphology of PS-PDMS Diblock Copolymer Films

Andersen, T. H., Tougaard, S., Larsen, N. B., Amdal, K. & Johannsen, I., 2001, I : Journal of Electron Spectroscopy and Related Phenomena. 121, s. 93-110

Analysis of angle-resolved electron energy loss in XPS spectra of Ag, Au, Co, Cu, Fe and Si

Simonsen, A. C., Youbero, F. & Tougaard, S., 1999, I : Surface Science. 436, 1, s. 149-159

Escape Probability of Electrons from Solids. Influence of Elastic Electron Scattering

Jablonski, A. & Tougaard, S., 1999, I : Surf. Sci.. 432, s. 211-27

Nanostructure of Ge deposited on Si(001): a study by XPS peak shape analysis and AFM

Simonsen, A. C., Schleberger, M., Tougaard, S., Lundsgaard Hansen, J. & Nylandsted Larsen, A., 1999, I : Thin Solid Films. 338, 1-2, s. 165-71 7 s.

Quantification of Au deposited on Ni: XPS peak shape analysis compared to RBS

Simonsen, A. C., Pøhler, J. P., Jeynes, C. & Tougaard, S., 1999, I : Surface and Interface Analysis. 27, 1, s. 52-56 5 s.

Ge growth on Si(001) studied by x-ray photoelectron spectroscopy peakshape analysis and atomic force microscopy

Schleberger, M., Simonsen, A. C., Tougaard, S., Lundsgaard Hansen, J. & Nylandsted Larsen, A., 1. nov. 1997, I : Journal of Vacuum Science & Technology. A. Vacuum, Surfaces, and Films. 15, 6, s. 3032-3035 4 s.

Quantitative model of electron energy loss in XPS

Simonsen, A. C., Yubero, F. & Tougaard, S., 15. jul. 1997, I : Physical Review B. 56, 3, s. 1612-1619 8 s.

Quantitative XPS: non-destructive analysis of surface nano-structures

Tougaard, S. M., jul. 1996, I : Applied Surface Science. 100-101, s. 1-10

Deconvolution of inelastic background signal from XPS spectra of homogeneous solids

Tougaard, S. M. & Jørgensen, B., 1987, I : Surface Science. 182, 3, s. L253-L256

Quantitative non-destructive in-depth composition information from XPS

Tougaard, S. M., 1986, I : Surface and Interface Analysis. 8, 6, s. 257-260

Mechanisms for oxygen adsorption on the Si(110) surface studied by Auger electron spectroscopy

Tougaard, S., Morgen, P. & Onsgaard, J., 2. nov. 1981, I : Surface Science. 111, 3, s. 545-554 10 s.

Electron Emission from Solids During Ion Bombardment: Theoretical Aspects

Sigmund, P. & Tougaard, S. M., 1981, *Inelastic Particle-Surface Collisions: Proceedings of the Third International Workshop on Inelastic Ion-Surface Collisions Feldkirchen-Westerham, Fed. Rep. of Germany September 17-19, 1980*. Taglauer, E. & Heiland, W. (red.). Berlin: Springer, s. 2-37 (Springer Series in Chemical Physics, Bind 17).

ADSORPTION OF N₂ ON W(100) UNDER LONG EXPOSURE.

Winters, H. F., Morgen, P., Tougaard, S. & Onsgaard, J., 1. jan. 1980, s. 303-306. 4 s.

Scandium and lutetium surfaces studied by reflection electron energy-loss spectroscopy

Onsgaard, J., Tougaard, S., Morgen, P. & Ryborg, F., 1. jan. 1980, I : Journal of Electron Spectroscopy and Related Phenomena. 18, 1, s. 29-41 13 s.

SCANDIUM, YTTRIUM AND LUTETIUM SURFACES STUDIED BY ELECTRON SPECTROSCOPY.

Onsgaard, J., Tougaard, S., Morgen, P. & Ryborg, F., 1. jan. 1980, s. 1361-1364. 4 s.

Observation of changes in the electronic density of states at a Si (111) surface during adsorption of oxygen by Auger electron spectroscopy

Morgen, P., Onsgaard, J. H. & Tougaard, S., 1. dec. 1979, I : Applied Physics Letters. 34, 8, s. 488-490 3 s.

Segregation of impurities at the surface of a scandium single crystal

Onsgaard, J., Tougaard, S. & Morgen, P., 1. jan. 1979, I : Applications of Surface Science. 3, 1, s. 113-117 5 s.

Desorption from powdered ZnO during electron bombardment and interaction with atomic hydrogen

Morgen, P., Onsgaard, J. H. & Tougaard, S., 1. dec. 1977, I : Journal of Applied Physics. 48, 8, s. 3443-3447 5 s.

Conductivity of powdered ZnO with chemisorbed oxygen during photodesorption

Morgen, P., Onsgaard, J. H. & Tougaard, S., 1. dec. 1976, I : Journal of Applied Physics. 47, 11, s. 5094-5096 3 s.

Aktiviteter

"Non-destructive characterization of nano-structures by analysis of the peak shape in photoelectron spectra"

Sven Mosbæk Tougaard (Foredragsholder)

20. jan. 2013 → 23. jan. 2013

"Quantitative XPS: effects of core-hole and surface excitations"

Sven Mosbæk Tougaard (Foredragsholder)

26. aug. 2010

"Simple universal curve for the energy dependent electron attenuation length for all materials" (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

2012 → ...

> Industrial Application Division

Sven Mosbæk Tougaard (Gæsteforsker)

20. jan. 2013 → 23. jan. 2013

Invited talk at UKSAF meeting in Newcastle: "Quantitative XPS of surface nano-structures by analysis of the peak shape"

Sven Mosbæk Tougaard (Foredragsholder)

9. jan. 2007

Invited Talk held at Univ of Newcastle: "Characterization of morphology and electronic properties of surface nano-structures by photo- and reflection electron spectroscopy"

Sven Mosbæk Tougaard (Foredragsholder)

10. jan. 2007

Invited talk at "Practical Surface Analysis 07" in Kanazawa Japan: "Algorithm for Automatic XPS Data Analysis: Quantification of Surface Nano-structures and Application to 3D-XPS Imaging"

Sven Mosbæk Tougaard (Foredragsholder)

28. nov. 2007

Invited talk at ECASIA: "Nano-Structure Information from XPS; Automatic Data Analysis and 3D-Imaging"

Sven Mosbæk Tougaard (Foredragsholder)

21. okt. 2009

Invited talk: "Characterization of nano-structured polymers by XPS-peak shape analysis"

Sven Mosbæk Tougaard (Foredragsholder)

17. jan. 2010

REELS as a quantitative method to characterize the electronic properties of surface nano-structures

Sven Mosbæk Tougaard (Foredragsholder)

20. jun. 2007

Surface excitation parameter: Theoretical determination and application in Monte Carlo simulations

Sven Mosbæk Tougaard (Foredragsholder)

22. okt. 2009

Talk at "Samsung Advanced Institute of Technology" , Seoul Korea: "Algorithm for Automatic XPS Data Analysis: Quantification of Surface Nano-structures and Application to 3D-XPS Imaging"

Sven Mosbæk Tougaard (Foredragsholder)

10. jan. 2009

Talk at "American Vacuum Society 55th International Symposium": "3-Dimensional XPS Imaging of Surface Nano-structures; A New Technique"

Sven Mosbæk Tougaard (Foredragsholder)

22. okt. 2008

Talk at Chungbuk National University, Korea: "Algorithm for Automatic XPS Data Analysis: Quantification of Surface Nano-structures and Application to 3D-XPS Imaging"

Sven Mosbæk Tougaard (Foredragsholder)

19. mar. 2008

32nd European Conference On Surface Science (ECOSS-32)

Sven Mosbæk Tougaard (Arrangør)

28. aug. 2016 → 2. sep. 2016

6th International Conference on Theoretical and Applied Physics (6th ICTAP)

Sven Mosbæk Tougaard (Arrangør)

19. sep. 2016 → 21. sep. 2016

6th International Symposium on Flexible Organic Electronics

Sven Mosbæk Tougaard (Deltager)

7. jul. 2013 → 11. jul. 2013

7th International Symposium on Practical Surface Analysis (PSA-16)

Sven Mosbæk Tougaard (Arrangør)

16. okt. 2016 → 21. okt. 2016

8th International Symposium on Practical Surface Analysis (PSA-19),

Sven Mosbæk Tougaard (Program komite medlem)

nov. 2019

A Near Real-time Data Analysis Package to Enhance the Information Extracted from XPS Spectra

Sven Mosbæk Tougaard (Andet)

25. aug. 2010

AIP The Journal of Chemical Physics (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

15. feb. 2011

American Vacuum Society 59th annual meeting

Sven Mosbæk Tougaard (Deltager)

2012

Analytical and Bioanalytical Chemistry (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2009

Analytical Sciences (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

2010

Applied Surface Science (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

8. mar. 2018

Applied Surface Science (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

1. okt. 2018

Applied Surface Science, Elsevier (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

3. maj 2016

Applied Surface Science, Elsevier (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

29. maj 2016

Arranged a Tutorial at Lokey Laboratories, University of Oregon: Using QUASES for Quantitative XPS and Auger Analysis of Surface Nanostructures

Sven Mosbæk Tougaard (Andet)

28. apr. 2009

Automated XPS analysis and XPS-Imaging of nano-structures

Sven Mosbæk Tougaard (Foredragsholder)

13. okt. 2010 → ...

Bedømmelsesudvalg for "Fonds de la Recherche Scientifique - FNRS", Belgium. (Ekstern organisation)

Sven Mosbæk Tougaard (Medlem)

1. feb. 2009 → 12. feb. 2009

Bedømmelsesudvalg for "Fonds de la Recherche Scientifique - FNRS", Belgium. (Ekstern organisation)

Sven Mosbæk Tougaard (Medlem)

31. mar. 2010 → 15. apr. 2010

Ca 15 papers i 5 forskellige internationale tidsskrifter (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2007

Censor i Faststoffysik på Aarhus Universitet

Sven Mosbæk Tougaard (Censor)

14. jan. 2015 → 16. jan. 2015

Censor i Faststoffysik på Aarhus Universitet

Sven Mosbæk Tougaard (Censor)

23. mar. 2015

Characterization of morphology of nano-structures by XPS

Sven Mosbæk Tougaard (Foredragsholder)

2. apr. 2014

Characterization of morphology of nano-structures by XPS

Sven Mosbæk Tougaard (Foredragsholder)

8. apr. 2014

Characterization of nano-structured materials with XPS-peak shape analysis

Sven Mosbæk Tougaard (Foredragsholder)

17. aug. 2010 → ...

Characterization of nano-structured materials with XPS-peak shape analysis

Sven Mosbæk Tougaard (Foredragsholder)

20. aug. 2010

Charles University

Sven Mosbæk Tougaard (Gæsteforsker)

11. nov. 2009 → 13. nov. 2009

Combining high-resolution core-level and inelastic background analysis in HAXPES to investigate deeply buried interfaces

Sven Mosbæk Tougaard (Foredragsholder)

2. okt. 2015

Course: QUASES Analysis

Sven Mosbæk Tougaard (Underviser)

25. sep. 2018

Czech Academy of Sciences

Sven Mosbæk Tougaard (Gæsteforsker)

10. nov. 2009

Danmarks Tekniske Universitet (Ekstern organisation)

Sven Mosbæk Tougaard (Medlem)

19. dec. 2014

ECASIA 19

Sven Mosbæk Tougaard (Program komite medlem)

sep. 2019

ECASIA-13

Sven Mosbæk Tougaard (Arrangør)

19. okt. 2013

ECASIA-15 European Conference on Applications of Surface and Interface Analysis

Sven Mosbæk Tougaard (Arrangør)

27. sep. 2015 → 2. okt. 2015

Ecole Thematique: "Workshop on XPS analysis"

Sven Mosbæk Tougaard (Arrangør)

27. sep. 2016 → 28. sep. 2016

Effective Attenuation Lengths for Photoelectrons in Thin Films of Silicon Oxynitride and Hafnium Oxynitride on Silicon (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

2012 → ...

European Conference on Surface Science (ECOSS)

Sven Mosbæk Tougaard (Arrangør)

30. aug. 2014 → 5. sep. 2014

European Synchrotron Radiation Facility

Sven Mosbæk Tougaard (Gæsteforsker)

10. jul. 2015 → 14. jul. 2015

External examiner on PhD thesis at Tampere University of Technology, Finland: "Oxidation Induced Nanostructures on Copper Alloy and Austenitic Steel Surfaces Studied by Electron Spectroscopic Methods"

Sven Mosbæk Tougaard (Censor)

4. okt. 2007

External examiner on PhD thesis at Helsinki University of Technology: "Development of XPS Data Analysis and its Application to Gas Sensor and Catalyst Surface Studies."

Sven Mosbæk Tougaard (Censor)

14. aug. 2007

Extrinsic and intrinsic effects in XPS: Validity of the two-step model and corrections for surface and core-hole effects

Sven Mosbæk Tougaard (Foredragsholder)

3. aug. 2011

Extrinsic and Intrinsic Effects in XPS: Validity of the two-step model and corrections for surface and core-hole effects

Sven Mosbæk Tougaard (Foredragsholder)

13. okt. 2010 → ...

Factor Analysis and Advanced Background Analysis methods to solve the problem of ... (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

2013 → ...

Founder and director of the software company: "QUASES-Tougaard ApS" (Ekstern organisation)

Sven Mosbæk Tougaard (Medlem)

20. feb. 1994 → ...

Gave a course for Industry and PhD students from USA, UK and central Europe

Sven Mosbæk Tougaard (Underviser)

22. mar. 2017

Gave a course for Industry and PhD students held at University of Surrey, UK: "SURFACE ANALYSIS: AN INTRODUCTION TO XPS, SCANNING AUGER MICROSCOPY AND SECONDARY ION MASS SPECTROMETRY": PhD kursus

Sven Mosbæk Tougaard (Underviser)

23. apr. 2007 → 27. apr. 2007

Gave a course for Industry and PhD students held at University of Surrey, UK: "Surface Analysis: XPS, Auger and SIMS": PhD kursus

Sven Mosbæk Tougaard (Foredragsholder)

18. mar. 2013 → 22. mar. 2013

Gave a course for Industry and PhD students held at University of Surrey, UK: "Surface Analysis: XPS, Auger and SIMS": Quantitative Analysis of Surfaces by Electron Spectroscopy' and software tutorial on applications of Quases-Tougaard software packages

Sven Mosbæk Tougaard (Foredragsholder)

24. mar. 2015 → 25. mar. 2015

Gave a one day course on quantitative XPS of nano-structured materials

Sven Mosbæk Tougaard (Underviser)

6. jul. 2017

Gave a workshop: XPS analysis using the QUASES-Tougaard software packages at the ECASIA conference

Sven Mosbæk Tougaard (Underviser)

27. sep. 2015

Growth of silver on ZnO and SnO₂ thin films intended for low emissivity applications (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

2012

Hasanuddin University

Sven Mosbæk Tougaard (Gæsteforsker)

30. mar. 2014 → 5. apr. 2014

ICPPC-2010 International Conference on Polymer Processing and Characterization

Sven Mosbæk Tougaard (Deltager)

15. jan. 2010 → 19. jan. 2010

Imperial College Press, London: Electron Elastic Scattering and Inelastic Scattering in Surface Electron Spectroscopy (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

4. okt. 2011

Institute Of Physics IOP Nanotechnology (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Instituto de Ciencia de Materiales de Sevilla

Sven Mosbæk Tougaard (Gæsteforsker)

14. mar. 2010 → 19. mar. 2010

Instituto de Ciencia de Materiales de Sevilla

Sven Mosbæk Tougaard (Gæsteforsker)

26. jan. 2014 → 31. jan. 2014

International Congress on Materials and Renewable Energy (MRE 2013)

Sven Mosbæk Tougaard (Deltager)

1. jul. 2013 → 3. jul. 2013

Intrinsic and Extrinsic Excitations in XPS (and AES): Validity of the two-step model and corrections for surface and core hole effects

Sven Mosbæk Tougaard (Foredragsholder)

19. aug. 2010

Invited Albert Nerken Award lecture: "Characterization of thin-film nano-structures by XPS"

Sven Mosbæk Tougaard (Foredragsholder)

29. okt. 2012

Invited talk at NanoTech Insight 2007 Luxor, Egypt: "Characterization of morphology and electronic properties of surface nano-structures by photo- and reflection electron spectroscopy"

Sven Mosbæk Tougaard (Foredragsholder)

16. mar. 2007

Invited talk at workshop "Optimizing Information Content of X-ray Photoelectron Spectroscopy Analys" at University of Oregon, USA: "Quantitative and non-destructive in-depth analysis of surface nano-structures"

Sven Mosbæk Tougaard (Foredragsholder)

27. apr. 2009

Invited talk at "55th IUVESTA workshop: Electron Transport Parameters; Applications in Surface Analysis": "3-Dimensional XPS Imaging of Surface Nano-structures; A New Technique"

Sven Mosbæk Tougaard (Foredragsholder)

15. sep. 2008

INVITED TALK Novel Applications of Inelastic Background Analysis: HAXPES and 3D Imaging

Sven Mosbæk Tougaard (Underviser)

24. sep. 2018

Invited talk: "Analytical Approach for Quantitative Surface Chemical Analysis using AES and XPS"

Sven Mosbæk Tougaard (Foredragsholder)

2013

Invited talk: "Characterization of Nano-structures from Analysis of the XPS Background: Automation and 3D-imaging"

Sven Mosbæk Tougaard (Foredragsholder)

29. okt. 2011 → 5. nov. 2011

Invited talk: "Nano-structure Information from XPS; Automated data analysis and 3D-imaging"

Sven Mosbæk Tougaard (Foredragsholder)

4. okt. 2010

Invited talk: "Nano-Structure Information from XPS; Automated Data Analysis and 3D-Imaging"

Sven Mosbæk Tougaard (Oplægsholder)

24. aug. 2010

Invited talk: "Quantitative XPS: Getting the Most Out of Your Instrument"

Sven Mosbæk Tougaard (Underviser)

5. jul. 2017

Invited talk: New developments (since last PSA 16) in Practical Applications of Inelastic Background Analysis to Characterize nano-structures

Sven Mosbæk Tougaard (Underviser)

5. nov. 2019

Invited talk: Novel Applications of XPS-Inelastic Background Analysis: 3D imaging and HAXPES

Sven Mosbæk Tougaard (Underviser)

17. okt. 2017

Invited Tutorial at workshop "Optimizing Information Content of X-ray Photoelectron Spectroscopy Analys" at University of Oregon, USA: "QUASES software applied to XPS-Nanostructure Characterization"

Sven Mosbæk Tougaard (Foredragsholder)

28. apr. 2009

Invitet talk: "Non-Destructive Characterization of Nano-Structures by XPS"

Sven Mosbæk Tougaard (Foredragsholder)
2013

IVC18- International Vacuum Congress

Sven Mosbæk Tougaard (Oplægsholder)
7. aug. 2010

J of Physics: Condensed Matter (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)
1. jan. 2008

J Phys D: Applied Physics (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)
1. jan. 2009

J. Electron Spectroscopy and Related Phenomena, Elsevier (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)
6. maj 2015

J. of Physics: Condensed Matter: The validity of semi-classical approach in calculation of surface excitation parameter (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)
23. jun. 2011

J. Phys. D: Appl. Phys (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)
1. jan. 2009

J. Phys. D: Applied Phys (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)
1. jan. 2009

Jopurnal Electron Spectroscopy (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)
1. jan. 2009

Journal Electron Spectroscopy (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)
1. jan. 2008

Journal Electron Spectroscopy (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)
1. jan. 2009

Journal Electron Spectroscopy and Related Phenomena (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)
1. jan. 2010

Journal Electron Spectroscopy, Elsevier (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)
8. apr. 2015

Journal Electron Spectroscopy, Elsevier (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

13. jan. 2013

Journal of Applied Physics (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

JOURNAL OF APPLIED PHYSICS (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

JOURNAL OF APPLIED PHYSICS (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

JOURNAL OF APPLIED PHYSICS (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Journal of Electron Spectroscopy (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Journal of Electron Spectroscopy and Related Phenomena (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

20. jun. 1988 → 1. jan. 2012

Journal of Electron Spectroscopy and Related Phenomena (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Journal of Electron Spectroscopy, Elsevier (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

9. jun. 2016

Journal of Materials Chemistry (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2010

Journal of Physics (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Journal of Physics D: Applied Physics (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2009

Journal of Physics D: Applied Physics (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2009

Journal of Surface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 1994 → ...

Journal of Surface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Journal of Surface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Journal of Surface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

2010

Journal of Electron Spectroscopy (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2009

Journal Surface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

2010

Journal Vacuum Science and Technology (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Julius-Maximilian University of Würzburg

Sven Mosbæk Tougaard (Gæsteforsker)

22. jun. 2009 → 24. jun. 2009

Julius-Maximilian University of Würzburg

Sven Mosbæk Tougaard (Gæsteforsker)

6. jun. 2011 → 18. jun. 2011

Julius-Maximilian University of Würzburg

Sven Mosbæk Tougaard (Gæsteforsker)

25. jul. 2011 → 6. aug. 2011

Keynote Speaker: Novel applications of inelastic background analysis: 3D imaging and HAXPES

Sven Mosbæk Tougaard (Foredragsholder)

17. okt. 2016

Leader of research program supported by BCR, EU (Ekstern organisation)

Sven Mosbæk Tougaard (Medlem)

1. jan. 1989 → 31. dec. 1994

Leader of the international research program: "Tests of Algorithms for Data Processing in XPS under Versailles Project on Advanced Materials and Standards (VAMAS)" (Ekstern organisation)

Sven Mosbæk Tougaard (Medlem)

1. jan. 1997 → 1. feb. 2007

Materials Science Center

Sven Mosbæk Tougaard (Gæsteforsker)

20. okt. 2007 → 27. okt. 2007

Member of *Center of Excellence: "Surface Phenomena and Reactions"* (Ekstern organisation)

Sven Mosbæk Tougaard (Medlem)

1. feb. 2003 → 1. feb. 2007

Member of International Program Advisory Board for "International Symposium on Surface Science -Focusing on Nano-, Green, and Biotechnologies- (ISSS-6)"

Sven Mosbæk Tougaard (Arrangør)

28. jan. 2010 → 15. dec. 2011

Member of Program Committee for "5th International Symposium on Practical Surface Analysis (PSA-10)"

Sven Mosbæk Tougaard (Arrangør)

1. nov. 2009 → 10. okt. 2010

Member of Program Committee for 5th International Symposium on Practical Surface Analysis

Sven Mosbæk Tougaard (Arrangør)

21. okt. 2010 → ...

Member of Program Committee for European Conference for Surface and Interface Analysis

Sven Mosbæk Tougaard (Arrangør)

4. sep. 2011

Member of steering committee for "European conference for applications of surface and interface analysis-ECASIA 09"

Sven Mosbæk Tougaard (Arrangør)

16. okt. 2009 → 23. okt. 2009

Member of the International Steering Committee for the conference: "European Conference on Applications of Surface and Interface Analysis (ECASIA-07)"

Sven Mosbæk Tougaard (Arrangør)

9. sep. 2007 → 14. sep. 2007

Member of the Program Committee for "55th IUVESTA Workshop on Electron Transport Parameters Applied in Surface Analysis"

Sven Mosbæk Tougaard (Arrangør)

14. sep. 2008 → 17. sep. 2008

Member of the Program Committee for "International Symposium on Practical Surface Analysis 2007", Japan

Sven Mosbæk Tougaard (Arrangør)

25. nov. 2007 → 28. nov. 2007

Member of the Program Committee for "2nd International Workshop on Hard X-ray Photoelectron Spectroscopy" at SPring-8, Japan

Sven Mosbæk Tougaard (Arrangør)

19. sep. 2006 → 20. sep. 2006

Member, since 2002 of the "International Steering Committee for European Conference on Applications of Surface and Interface Analysis (ECASIA)" (Ekstern organisation)

Sven Mosbæk Tougaard (Medlem)

20. apr. 2002 → ...

Model to correct XPS and AES for core hole-, transport- and surface effects. Validity and practical applications

Sven Mosbæk Tougaard (Foredragsholder)

1. sep. 2014

Nano Technology (Tidsskrift)
Sven Mosbæk Tougaard (Redaktør)
1. jan. 2008

Nanostructures Characterized by Electron Spectroscopy.
Sven Mosbæk Tougaard (Foredragsholder)
15. jun. 2011

Nanotechnology (Tidsskrift)
Sven Mosbæk Tougaard (Redaktør)
1. jan. 2008

Nanotechnology (Tidsskrift)
Sven Mosbæk Tougaard (Redaktør)
1. jan. 2008

National Institute for Materials Science
Sven Mosbæk Tougaard (Gæsteforsker)
10. okt. 2010 → 13. okt. 2010

National University of Singapore (Ekstern organisation)
Sven Mosbæk Tougaard (Medlem)
1. jan. 2009 → 1. mar. 2009

Near real time data analysis and other approaches to enhancing information from XPS
Sven Mosbæk Tougaard (Foredragsholder)
21. okt. 2009

New technique for non-destructive 3D-imaging of nano-structures
Sven Mosbæk Tougaard (Foredragsholder)
27. okt. 2010

Non-destructive imaging of nanostructures by analysis of the photoelectron peak shape
Sven Mosbæk Tougaard (Foredragsholder)
30. aug. 2016

Pacific Northwest National Laboratory
Sven Mosbæk Tougaard (Gæsteforsker)
28. apr. 2009 → 2. maj 2009

Paris Diderot University
Sven Mosbæk Tougaard (Gæsteforsker)
18. maj 2008 → 25. maj 2008

Participated in "The Latest in XPS Technology" meeting at Risoe, Denmark
Sven Mosbæk Tougaard (Deltager)
7. jun. 2007 → 8. jun. 2007

Participated in the international reserach project: "Synchrotron Microanalysis: accurate and traceable elemental analysis on the microscopic level" (Ekstern organisation)
Sven Mosbæk Tougaard (Medlem)
1. jan. 2000 → 1. jul. 2005

Physical Review B (Tidsskrift)
Sven Mosbæk Tougaard (Redaktør)

1. jan. 2009

Poster at "European Conference on Surface and Interface Analysis": "Characterization of Au nano-cluster formation on and diffusion in Polystyrene using XPS peak shape analysis"

Sven Mosbæk Tougaard (Foredragsholder)

10. sep. 2007

Poster at "European Conference on Surface and Interface Analysis": "Test of validity of the V-type trajectory assumption in REELS experiments"

Sven Mosbæk Tougaard (Foredragsholder)

13. sep. 2007

Poster at "European Conference on Surface and Interface Analysis": "Theoretical determination of the surface excitation parameter for Ti, Fe, Cu, Pd, Ag, and Au"

Sven Mosbæk Tougaard (Foredragsholder)

12. sep. 2007

Quantitative Analysis of Surfaces by Electron Spectroscopy

Sven Mosbæk Tougaard (Foredragsholder)

24. mar. 2015

Quantitative Analysis of Surfaces by Electron Spectroscopy. XPS and AES

Sven Mosbæk Tougaard (Keynote speaker)

26. sep. 2016 → 30. sep. 2016

Quantitative XPS of nano-structures with the Quases software-Practical applications and tutorial examples

Sven Mosbæk Tougaard (Foredragsholder)

19. okt. 2015 → 21. okt. 2015

Quantitative XPS: Effects of core-hole and surface excitations

Sven Mosbæk Tougaard (Foredragsholder)

7. okt. 2010 → ...

QUASES workshop

Sven Mosbæk Tougaard (Underviser)

27. sep. 2015

QUASES-workshop

Sven Mosbæk Tougaard (Arrangør)

27. sep. 2015

QUASES-XPS analysis of surface nano-structures

Sven Mosbæk Tougaard (Underviser)

16. jun. 2019 → 21. jun. 2019

REM8-8th International Meeting on recent developments in the study of radiation effects in matter

Sven Mosbæk Tougaard (Deltager)

20. sep. 2015 → 23. sep. 2015

Scientific leader of the international research program: "Determination of Standardized Parameters Describing the Electron Transport for Quantitative Surface Analysis by Electron Spectroscopies" (Ekstern organisation)

Sven Mosbæk Tougaard (Medlem)

1. jan. 1998 → 1. jan. 2002

Short Course on Quases-XPS analysis of nano-structured surfaces

Sven Mosbæk Tougaard (Underviser)

2. jul. 2019

Software Package to Calculate the Effects of Core hole and Surface Excitations on XPS and AES

Sven Mosbæk Tougaard (Foredragsholder)

6. sep. 2011

Spring-8, Japan: "Non-destructive characterization of nano-structures by analysis of the peak shape in photoelectron spectra "

Sven Mosbæk Tougaard (Foredragsholder)

21. jan. 2013

Surface Analysis 2009; 31st AVS-Symposium on Applied Surface Analysis

Sven Mosbæk Tougaard (Deltager)

22. apr. 2009 → 24. apr. 2009

Surface Analysis Course at Univ. of Surrey, UK

Sven Mosbæk Tougaard (Oplægsholder)

2013

Surface and Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 1987 → ...

Surface and Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Surface and Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Surface and Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Surface and Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Surface and Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Surface and Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2009

Surface and Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

1. nov. 2010

Surface and Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

13. sep. 2018

Surface and Interface Analysis, Wiley (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

20. maj 2016

Surface and Interface Analysis, Wiley (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

25. jun. 2016

Surface and Interface Analysis, Wiley (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

15. jul. 2016

Surface Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Surface Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Surface Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Surface Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Surface Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2009

Surface Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2010

Surface Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2010

Surface Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2010

Surface Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2010

Surface Interface Analysis (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

7. sep. 2010

Surface Interface Analysis (Tidsskrift)
Sven Mosbæk Tougaard (Peer reviewer)
2010

Surface Interface Analysis (Tidsskrift)
Sven Mosbæk Tougaard (Peer reviewer)
12. jan. 2011

Surface Interface Analysis (Tidsskrift)
Sven Mosbæk Tougaard (Peer reviewer)
sep. 2013

Surface Interface Analysis (Tidsskrift)
Sven Mosbæk Tougaard (Peer reviewer)
okt. 2013

Surface Interface Analysis (Tidsskrift)
Sven Mosbæk Tougaard (Peer reviewer)
12. nov. 2013

Surface Interface Analysis (Tidsskrift)
Sven Mosbæk Tougaard (Peer reviewer)
18. nov. 2013

Surface Interface Analysis (Tidsskrift)
Sven Mosbæk Tougaard (Peer reviewer)
1. nov. 2018

Surface Interface Analysis- Wiley (Tidsskrift)
Sven Mosbæk Tougaard (Peer reviewer)
feb. 2014

Surface Interface Analysis- Wiley (Tidsskrift)
Sven Mosbæk Tougaard (Peer reviewer)
nov. 2018 → ...

Surface Interface Analysis, Wiley (Tidsskrift)
Sven Mosbæk Tougaard (Peer reviewer)
21. feb. 2014

Surface Interface Analysis, Wiley (Tidsskrift)
Sven Mosbæk Tougaard (Peer reviewer)
maj 2015

Surface Interface Analysis, Wiley (Tidsskrift)
Sven Mosbæk Tougaard (Peer reviewer)
14. aug. 2015

Surface Interface Analysis, Wiley (Tidsskrift)
Sven Mosbæk Tougaard (Peer reviewer)
19. sep. 2015 → ...

Surface Interface Analysis, Wiley (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

30. okt. 2015

Surface Interface Analysis, Wiley (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

okt. 2018

Surface Interface Analysis: "An accurate ..." (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

2011

Surface Interface Analysis: "Assessment of the thickness of SiO₂ layers through XPS measurements employing experimental and theoretical values of β " (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

27. feb. 2012

Surface Interface Analysis: "Improved ARXPS.." (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

2011

Surface Interface Analysis: "Systematic Calculation of the Surface Excitation Parameters for 25 Materials" (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

2012 → ...

Surface Science (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Surface Science (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Surface Science (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Surface Science (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Surface Science (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Surface Science (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2008

Surface Science (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)

1. jan. 2009

Surface Science (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)

aug. 2013

Surface Science (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)
2014 → ...

Surface Science (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)
29. dec. 2014

Surface Science (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)
apr. 2018

Surface Science Spectra (Tidsskrift)

Sven Mosbæk Tougaard (Redaktør)
20. maj 1989 → ...

Surface Science Spectra (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)
18. mar. 2016

Surface Science Spectra (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)
16. dec. 2018

Surface Science Spectra (Tidsskrift)

Sven Mosbæk Tougaard (Peer reviewer)
22. dec. 2018

Syddansk Universitet

Sven Mosbæk Tougaard (Gæsteunderviser)
16. apr. 2013 → 19. apr. 2013

Syddansk Universitet

Sven Mosbæk Tougaard (Gæsteunderviser)
18. jul. 2016 → 25. jul. 2016

Syddansk Universitet (Ekstern organisation)

Sven Mosbæk Tougaard (Formand)
jan. 2014

Talk at "12th Joint Vacuum Conference (JVC-12)" in Hungary: "3-Dimensional XPS Imaging of Surface Nano-structures; A New Technique"

Sven Mosbæk Tougaard (Foredragsholder)
23. sep. 2008

Talk at "European Conference on Surface and Interface Analysis": Applicability of REELS to characterize the electronic properties of surface nano-structures"

Sven Mosbæk Tougaard (Foredragsholder)
10. sep. 2007

Talk at "Mads Clausen Institut", Sønderborg Denmark: "Characterization of Morphology and Electronic Properties of Surface Nano-structures with XPS and REELS"

Sven Mosbæk Tougaard (Foredragsholder)

26. feb. 2009

Talk at "Surface Analysis 2009; 31st AVS-Symposium on Applied Surface Analysis", California USA: "3-Dimensional XPS Imaging of Surface Nano-structures; A New Technique"

Sven Mosbæk Tougaard (Foredragsholder)

22. apr. 2009

Talk at Charles University in Prague: "Characterization of nano-structured materials with XPS-peak shape analysis"

Sven Mosbæk Tougaard (Foredragsholder)

11. nov. 2009

Talk at Helsinki University of Technology: "Characterization of chemical composition and electronic properties of nano-structures"

Sven Mosbæk Tougaard (Foredragsholder)

13. aug. 2007

Talk at Materials Science Center, Sevilla: "XPS Imaging of Nano-structures"

Sven Mosbæk Tougaard (Foredragsholder)

16. mar. 2010

Talk at Tampere University of Technology 2007: "Algorithm for Automatic XPS data analysis and applications to 3D XPS imaging"

Sven Mosbæk Tougaard (Foredragsholder)

10. aug. 2007

Talk at Universitaet Wuerzburg: "Nano-scale in-depth composition and electronic properties of nano-structured thin films determined with XPS and REELS"

Sven Mosbæk Tougaard (Foredragsholder)

23. jun. 2009

Talk at "55th IUVSTA Workshop: Electron Transport Parameters; Applications in Surface Analysis": "Validity of Yubero-Tougaard theory to quantitatively determine the dielectric properties of surface nanofilms"

Sven Mosbæk Tougaard (Foredragsholder)

16. sep. 2008

Talk at "Pacific Northwest National Laboratory", Washington-State, USA: "3-Dimensional Nano-Structure Information from X-Ray Photo Electron Spectroscopy"

Sven Mosbæk Tougaard (Foredragsholder)

30. apr. 2009

Talk at 2nd IEEE International Nanoelectronics Conference in Shaghai, China: "3-Dimensional XPS Imaging of Surface Nano-structures; A New Technique"

Sven Mosbæk Tougaard (Foredragsholder)

26. mar. 2008

Talk at "European Conference on Surface and Interface Analysis": "Tomography on the nanoscale by XPS; A new approach to visual 3D-imaging"

Sven Mosbæk Tougaard (Foredragsholder)

11. sep. 2007

The Centre of Physcial Experiments

Sven Mosbæk Tougaard (Gæsteforsker)

18. aug. 2010 → 22. aug. 2010

The Dielectric Function and its application in nano-structure characterization

Sven Mosbæk Tougaard (Foredragsholder)

3. apr. 2014

Ukendt (Ekstern organisation)

Sven Mosbæk Tougaard (Deltager)

19. okt. 2015 → 22. okt. 2015

University of Indonesia

Sven Mosbæk Tougaard (Gæsteforsker)

6. apr. 2014 → 9. apr. 2014

Visited "Applied Materials" - leader in Nanomanufacturing Technology solutions; Santa Clara, California, USA

Sven Mosbæk Tougaard (Vejleder)

20. apr. 2009

Visited "KLA-Tencor" - leading semiconductor equipment manufacturer; Santa Clara, California, USA

Sven Mosbæk Tougaard (Rådgiver)

21. apr. 2009

Workshop on QUASES-Tougaard XPS

Sven Mosbæk Tougaard (Underviser)

19. sep. 2019

Workshop on XPS-QUASES analysis

Sven Mosbæk Tougaard (Underviser)

28. sep. 2017

Writing Scientific Papers

Sven Mosbæk Tougaard (Foredragsholder)

1. apr. 2014